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Recent Topics on Modeling of Semiconductor Processes, Devices and Circuits

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About the ebook

The last couple of years have been very busy for the semiconductor industry and researchers.. This e-book focuses on the latest semiconductor techniques devised to address these issues. It should be a useful resource for electronic engineers and semiconductor chip designers.

Contents

- ▶ A Brief Overview of Lithographic Advancements in the Last Decade with a Focus on Double Patterning
- ▶ Interconnect Variability and Performance Analysis
- ▶ Compact Modeling for NBTI and CHC Effects
- ▶ Probability Propagation and Yield Optimization for Analog Circuits
- ▶ Compact Modeling of Engineered Strain
- ▶ Chip-Level Statistical Leakage Modeling and Analysis
- ▶ Mathematical Method for VLSI Thermal Simulation at the System and Circuit Levels

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